



FPD Materials & Components and FPD Metrology Japan Joint TC Chapter Meeting Summary and Minutes

Japan Standards Winter Meetings 2025
Monday, February 7, 2025, 3:00pm - 5:00pm JST
SEMI Japan/ Official Virtual TC Chapter Meeting (Hybrid)

TC Chapter Announcements

Next TC Chapter Meeting:

FPD Materials & Components Japan TC Chapter and FPD Metrology Japan TC Chapter joint meeting is scheduled for Friday, July 18, 2025, 3:30 PM - 5:00 PM JST via OVTCCM and at SEMI Japan, Tokyo.

Table 1 Meeting Attendees

Italics indicate virtual participants.

FPD Materials & Components TC Co-Chairs: Tadahiro Furukawa (Yamagata University), Ryoichi Watanabe (Japan Display), Toshimasa Eguchi (Sumitomo Bakelite)

FPD Metrology TC Co-Chairs: Ryoichi Watanabe (Japan Display), Akira Kawaguchi (Otsuka Electronics)

SEMI Staff: Keiko Kamejinaka (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>FUJIFILM</i>	<i>Ishizuka</i>	<i>Hiroshi</i>	<i>SK-Electronics</i>	<i>Yagi</i>	<i>Toshifumi</i>
<i>HOYA Corporation</i>	<i>Kondo</i>	<i>Keitaro</i>	<i>SK-Electronics</i>	<i>Miyazaki</i>	<i>Shohei</i>
Japan Display	Watanabe	Ryoichi	Yamagata University	Furukawa	Tadahiro
<i>Kei techno research</i>	<i>Ochi</i>	<i>Keizo</i>	SEMI Japan	Hirabara	Takeaki
<i>NIPPON STEEL Chemical & Material</i>	<i>Nakatsuka</i>	<i>Jun</i>	SEMI Japan	Yoshida	Akiko
<i>Otsuka Electronics</i>	<i>Kawaguchi</i>	<i>Akira</i>	SEMI Japan	Kamejinaka	Keiko
<i>Sumitomo Bakelite</i>	<i>Eguchi</i>	<i>Toshimasa</i>			

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
<i>FPD Materials & Components Japan TC Chapter</i>	
None	
<i>FPD Metrology Japan TC Chapter</i>	
None	

Table 4 Ballot Results

Document #	Document Title	Committee Action
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
7259A	Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality	Passed as balloted

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

#	Type	SC/TF/WG	Details
<i>FPD Materials & Components TC Chapter</i>			
None			
<i>FPD Metrology TC Chapter</i>			
None			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	Type	SC/TF/WG	Details
<i>FPD Materials & Components Japan TC Chapter</i>			
None			
<i>FPD Metrology Japan TC Chapter</i>			
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 7 Authorized Ballots

#	When	TF	Details
<i>FPD Materials & Components Japan TC Chapter</i>			
None			
<i>FPD Metrology Japan TC Chapter</i>			
None			

Table 8 SNARF(s) Granted a One-Year Extension

#	TF	Title	Expiration Date
<i>FPD Materials & Components Japan TC Chapter</i>			
None			
<i>FPD Metrology Japan TC Chapter</i>			
None			

Table 9 SNARF(s) Abolished

#	TF	Title
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
None		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	Title
<i>FPD Materials & Components Japan TC Chapter</i>	
None	
<i>FPD Metrology Japan TC Chapter</i>	
None	

Table 11 New Action Items

Item #	Assigned to	Details
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20250207-01	SEMI Staff	To forward f the ballot adjudication result of Doc. #7295A to A&R Subcommittee for procedural review.

Table 12 Previous Meeting Action Items

Item #	Assigned to	Details
<i>FPD Materials & Components Japan TC Chapter</i>		
FPDM&C_20241021_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7256, 7257, 7258 and 7260 to the ISC A&R Subcommittee for procedural review. →Closed
<i>FPD Metrology Japan TC Chapter</i>		
PDMet_20241021-01	FPD Metrology Maintenance Task Force	To submit Doc.#7259A, Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality for Cycle 9. →Closed

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa called the meeting to order at 3:00 PM JST. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 1_Required Meeting Elements March 2024_J

2 Review of Previous Meeting Minutes

The FPD Materials & Components Japan TC Chapter and the FPD Metrology Japan TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes as written.

By / 2nd: Ryoichi Watanabe/ Japan Display Inc. / Keizo Ochi/ Kei techno research

Discussion: None.

Vote: 8-Y 0-N. Motion Passed.

Attachment: 2_FPD M&C+FPD Met_JA _Mins_20241021_R1

3 Liaison Reports

3.1 FPD Metrology Korea TC Chapter

Keiko Kamejinaka (SEMI Japan) reported for the FPD Metrology Korea TC Chapter. Of note:

- The last TC Chapter meeting was held on October 24, 2024 and the next TC Chapter meeting is scheduled for March 20, 2025.
- There was a request for GCS Approval from FPD Metrology Korea TC Chapter on January 16, however due to the comments raised during the review period, the requests for SNARF approval (withdrawal of D61) and Ballot authorization (Cycle 2) remain pending. These will be forwarded to the ISC Regulations SC for further consideration.
- Document Number 6975D (Test Method for Response Time Evaluation of Displays with Variable Refresh Rate) proposed by Picture Quality Evaluation TF is published as D87 in January 2025.

Ryoichi Watanabe (Japan Display) provided an additional explanation regarding the current situation of D61. Of Note:

- It was found there were copyright issues with the previously published SEMI D61-1110 ‘Test Methods for Perceptual Angle of OLED Displays’, specifically some contents were referred from CIE Standard.
- The proceed is currently being considered.

Attachment: 3_Liaison report_FPDM_KR_Jab2025

3.2 FPD Metrology Taiwan TC Chapter

Keiko Kamejinaka (SEMI Japan) reported for the FPD Metrology Taiwan TC Chapter. Of note

- The last TC Chapter meeting was held on October 4, 2024 and the next TC Chapter meeting is scheduled for April 11, 2025.
- Submission of the following documents by Transparent Display TF for Cycle 9, 2024 was authorized.
 - Doc. #7294, Reapproval of SEMI D65-0719, Test Method for Measurement for the Color Breakup of Field Sequential Color Display
 - Doc. #7295, Reapproval of SEMI D68-0719, Test Method for Optical Properties of Electronic Paper Displays

- The following document is currently being reviewed by Transparent Display TF.
 - Reapproval of SEMI D56-0519, Test Method for Measurement for Ambient Contrast of Liquid Crystal Displays

Attachment: 4_Liaison Report_FPD_20241004_R1

4 SEMI Staff Report

Keiko Kamejinaka (SEMI Japan) gave the SEMI Staff Report. Of note:

- SEMICON Japan had successfully ended. The number of visitors exceeded the target of 100,000.
- By Feb 2025, all Standards Task Forces must use Connect@SEMI to host documents that are currently under development, and each Standards Task Force will have its own Community Page on Connect@SEMI.
- Procedure Manual has been updated to clarify the discharge and Dormant of a TF.

Attachment: 5_Staff Report January 2025

5 Ballot Review

NOTE 1: TC Chapter adjudication of ballots is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment file name for each balloted document is provided.

5.1 FPD Metrology Japan TC Chapter

5.1.1 *Doc.#7259A, Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality*

- **Passed** the TC Chapter review as balloted. Refer to the attachment below for full details.

Attachment: 6_7295A_Ballot Review_FPD-Metrology

6 Task Force Reports

6.1 FPD Materials & Components Japan TC Chapter

6.1.1 Flexible Display Task Force

Tadahiro Furukawa (Yamagata University) reported no update on this TF.

6.1.2 FPD Mask Task Force

Keitaro Kondo (HOYA Corporation) reported for the FPD Mask Task Force. Of note:

- Examinations and listed up of candidate materials for plate holder in blanks/mask case
 - To standardize the cases through blanks to mask, we will try to find better material that meets the specifications of the plate holder.
 - To reduce analysis costs, we will try to investigate with data obtained by each company already.
 - We will call other companies (blanks and mask makers) if they join the discussion.
- The next meeting is scheduled for February 13, 2025 JST 2:00pm by On-line

Attachment: 7_FPD_Mask TF_Minute_20241212

6.1.3 *FPD Materials & Components Maintenance Task Force*

Tadahiro Furukawa (Yamagata University) reported no update on this TF.

6.2 *FPD Metrology Japan TC Chapter*

6.2.1 *FPD Metrology Maintenance Task Force*

Doc. #7259A submitted for Cycle 9, 2024 under the FPD Metrology GTC passed the TC Chapter review, and the result will be forwarded to the ISC A&R SC for procedural review.

7 Old Business

7.1 *FPD Materials & Components Japan TC Chapter*

7.1.1 Project Period Review

No SNARF will be expiring soon.

7.1.2 5-year Review

No document is subject to 5-year review within this year.

7.2 *FPD Metrology Japan TC Chapter*

7.2.1 *Project Period Review*

No SNARF will be expiring soon.

7.2.2 *5-Year Reviews*

No document is subject to 5-year review within this year.

8 New Business

8.1 *FPD Materials & Components Japan TC Chapter*

None.

8.2 *FPD Metrology Japan TC Chapter*

None.

9 Action Item Review

9.1 *Open Action Items*

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
FPDM&C_20241021_01	SEMI Staff	To forward the ballot result of Doc.#7256, 7257, 7258 and 7260 to the ISC A&R Subcommittee for procedural review. →Closed
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20241021-01	FPD Metrology Maintenance Task Force	To submit Doc.#7259A, Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality for Cycle 9. →Closed



9.2 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20250207-01	SEMI Staff	To forward the ballot adjudication result of Doc. #7259A to the ISC A&R Subcommittee for procedural review.

10 Next Meeting and Adjournment

FPD Materials & Components Japan TC Chapter and FPD Metrology Japan TC Chapter joint meeting is scheduled for Friday, July 18, 2025, 3:30pm - 5:00pm JST via OVTCCM and at SEMI Japan, Tokyo, Japan.

See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: [5:00pm JST].

Respectfully submitted by:

Keiko Kamejinaka, SEMI Japan

Email: kkamejinaka@semi.org

Minutes tentatively approved by:

<i>FPD Materials & Components Japan TC Chapter</i>	
Tadahiro Furukawa (Yamagata University), Co-chair	February 20, 2025
Ryoichi Watanabe (Japan Display), Co-chair	February 19, 2025
Toshimasa Eguchi (Sumitomo Bakelite), Co-chair	February 20, 2025
<i>FPD Metrology Japan TC Chapter</i>	
Ryoichi Watanabe (Japan Display), Co-chair	February 19, 2025
Akira Kawaguchi (Otsuka Electronics), Co-chair	February 20, 2025

Table 13 Index of Available Attachments^{#1}

<i>Title</i>	<i>Title</i>
1_Required Meeting Elements March 2024_J	5_Staff Report January 2025
2_FPD M&C+FPD Met_JA_Mins_20241021_R1	6_7295A_Ballot Review_FPD-Metrology
3_Liaison report_FPDM_KR_Jab2025	7_FPD_Mask TF_Minute_20241212
4_Liaison Report_FPD_20241004_R1	

^{#1} Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Akiko Yoshida at the contact information above.